

F-6971

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FOREIGN PATENT DOCUMENTS							
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							Yes No
TRANSLATION KEY: * English Abstract. <sup>F</sup> Concise statement of relevance provided in foreign search report. <sup>C</sup> Concise statement of relevance provided in specification. <sup>S</sup> Concise statement of relevance provided in IDS. <sup>P</sup> Relevant portion of reference translated. <sup>O</sup> English abstract only - copy of reference in pct search.							
OTHER INFORMATION DISCLOSURE CITATIONS (Including Author, Title, Date, Pertinent Pages, Etc.)							
		1997 - X-ray Reflectometer for the Diagnostics of Thin Films During Growth, U. Niggemeier, K. Lischka, W. M. Plotz and V. Holy, Journal of Applied Crystallography, Volume 30, Pages 905-908					
EXAMINER Hoon K. Song				DATE CONSIDERED			
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